



# **Description**

The XPX7528RX uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

### **Application**

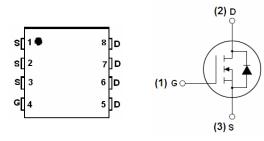
- Secondary side synchronous rectifier
- High side switch in POL DC/DC converter

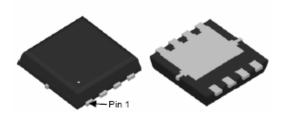


V DS =30V,ID =100A

 $RDS(ON) = 2.8 m\Omega @ VGS = 10V$ 

RDS(ON) =4.5m $\Omega$  @ VGS=4.5V





### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX7528RX	XPX7528RX	DFN 3x3-8	-	-	5000

#### Absolute Maximum Ratings (T<sub>C</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	I <sub>D</sub>	100	А
Drain Current-Continuous(T <sub>C</sub> =100 °C)	I <sub>D</sub> (100℃)	65	Α
Pulsed Drain Current (Note 1)	I <sub>DM</sub>	350	А
Maximum Power Dissipation	P <sub>D</sub>	70	W
Derating factor		3.2	W/°C
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	121	mJ
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 150	$^{\circ}$
Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	R <sub>eJC</sub>	2.15	°C/W



# **Electrical Characteristics** (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Static Cha	aracteristics					,
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	30	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V	1		1	
		T <sub>J</sub> =85°C	-	-	30	μА
$V_{\rm GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = 250 \mu A$	1.0	1.5	2.5	V
$I_{\rm GSS}$	Gate Leakage Current	$V_{GS}$ =±20V, $V_{DS}$ =0V	-	-	±100	nA
	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =20A	-	2.8	3.8	mΩ
$R_{DS(ON)}^{d}$		T <sub>J</sub> =125°C	ı	4.4	-	
		$V_{GS}$ =4.5V, $I_{DS}$ =20A	-	4.5	5.5	
Gfs	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =20A	-	24.6	-	S
Diode Ch	aracteristics					
$V_{\text{SD}}^{}\text{d}}$	Diode Forward Voltage	I <sub>SD</sub> =20A, V <sub>GS</sub> =0V	-	8.0	1.1	V
t <sub>rr</sub>	Reverse Recovery Time		-	35.6	-	
t <sub>a</sub>	Charge Time	1 =20A dl /dt=100A/.a	-	19.3	-	ns
t <sub>b</sub>	Discharge Time	$I_{DS}$ =20A, $dI_{SD}/dt$ =100A/ $\mu$ s	-	16.3	-	
Q <sub>rr</sub>	Reverse Recovery Charge		-	26	-	nC
Dynamic	Characteristics <sup>e</sup>	,				,
$R_{G}$	Gate Resistance	V <sub>GS</sub> =0V,V <sub>DS</sub> =0V,F=1MHz	-	1	2	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V,	-	1968	2818	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =15V,	-	850	-	
C <sub>rss</sub>	Reverse Transfer Capacitance	Frequency=1.0MHz	-	185	-	
t <sub>d(ON)</sub>	Turn-on Delay Time		-	12.4	23	
t <sub>r</sub>	Turn-on Rise Time	$V_{DD}$ =15V, $R_L$ =15 $\Omega$ ,	-	9.5	18	
t <sub>d(OFF)</sub>	Turn-off Delay Time	$I_{DS}$ =1A, $V_{GEN}$ =10V, $R_{G}$ =6 $\Omega$	-	27.2	49	ns
t <sub>f</sub>	Turn-off Fall Time		-	35.2	64	
Gate Cha	rge Characteristics <sup>e</sup>					
$Q_g$	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>DS</sub> =20A	-	20.6	28.8	
$Q_g$	Total Gate Charge		-	9.8	-	
$Q_{gth}$	Threshold Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V,	-	1.8	-	nC
$Q_{gs}$	Gate-Source Charge	I <sub>DS</sub> =20A	-	3.8	-	
$Q_{gd}$	Gate-Drain Charge		-	3.7	-	

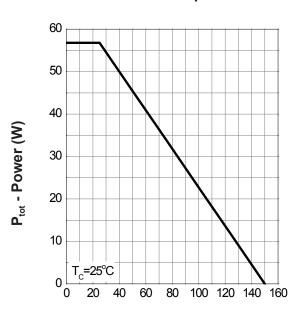
Note d : Pulse test ; pulse width $\leq 300 \mu s$ , duty cycle $\leq 2\%$ .

Note e : Guaranteed by design, not subject to production testing.



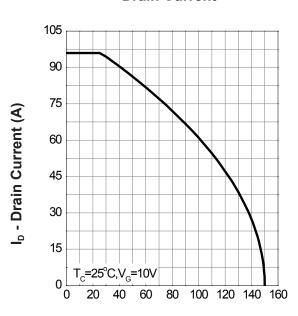
# **Typical Operating Characteristics**





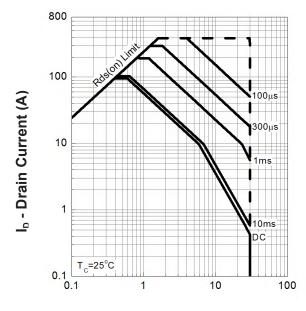
T<sub>i</sub> - Junction Temperature (°C)

#### **Drain Current**



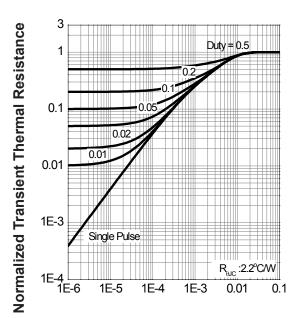
T<sub>i</sub> - Junction Temperature (°C)

### **Safe Operation Area**



V<sub>DS</sub> - Drain - Source Voltage (V)

### **Thermal Transient Impedance**

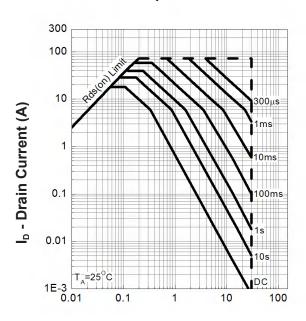


**Square Wave Pulse Duration (sec)** 



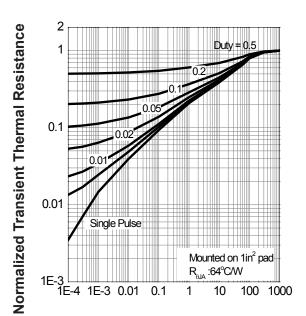
# **Typical Operating Characteristics(Cont.)**

# **Safe Operation Area**



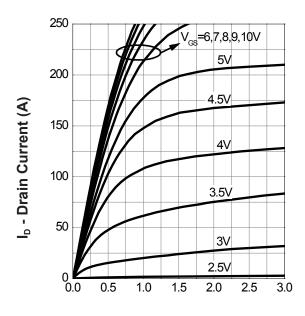
V<sub>DS</sub> - Drain - Source Voltage (V)

### **Thermal Transient Impedance**



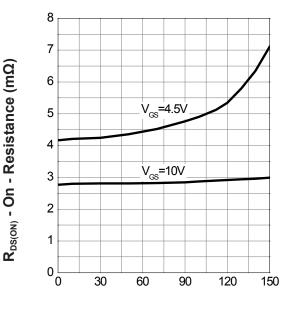
**Square Wave Pulse Duration (sec)** 

# **Output Characteristics**



V<sub>DS</sub> - Drain - Source Voltage (V)

#### **Drain-Source On Resistance**

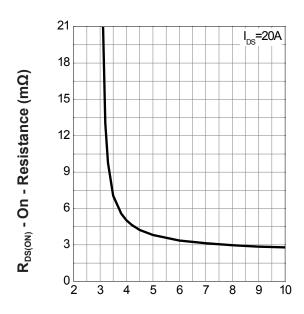


I<sub>D</sub> - Drain Current (A)



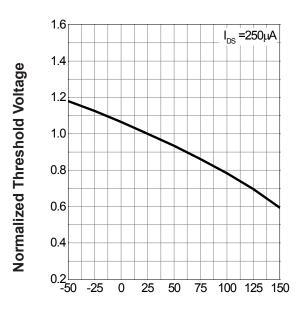
# **Typical Operating Characteristics(Cont.)**

#### **Gate-Source On Resistance**



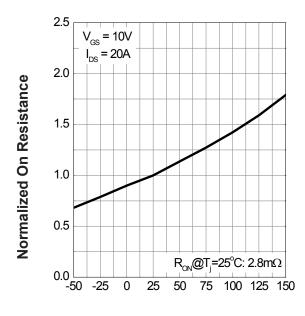
V<sub>GS</sub> - Gate - Source Voltage (V)

### **Gate Threshold Voltage**



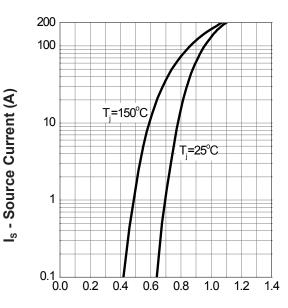
T<sub>i</sub> - Junction Temperature (°C)

### **Drain-Source On Resistance**



T<sub>j</sub> - Junction Temperature (°C)

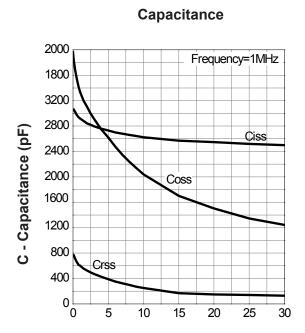
#### Source-Drain Diode Forward



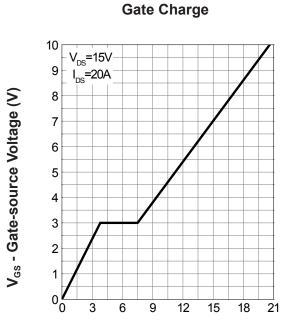
V<sub>SD</sub> - Source - Drain Voltage (V)



# **Typical Operating Characteristics(Cont.)**

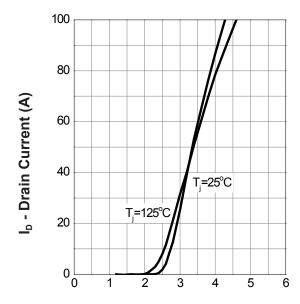


V<sub>DS</sub> - Drain-Source Voltage (V)



Q<sub>G</sub> - Gate Charge (nC)

#### **Transfer Characteristics**

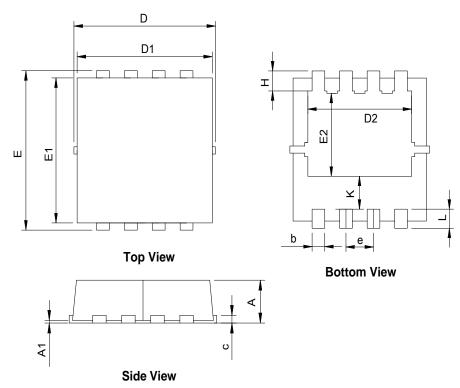


V<sub>GS</sub> - Gate-Source Voltage (V)



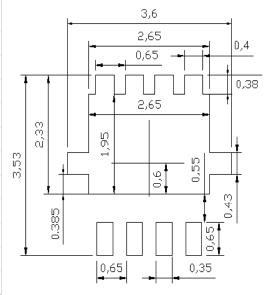
# **Package Information**

DFN3.3x3.3A-8\_EP1\_P



Ş	DFN3.3x3.3A-8_EP1_P				
SYMBOL	MILLIMETERS		INCHES		
L	MIN.	MAX.	MIN.	MAX.	
Α	0.70	1.00	0.028	0.039	
A1	0.00	0.05	0.000	0.002	
b	0.25	0.35	0.010	0.014	
С	0.10	0.25	0.004	0.010	
D	3.10	3.50	0.122	0.138	
D1	3.05	3.25	0.120	0.128	
D2	2.35	2.59	0.093	0.102	
Е	3.10	3.50	0.122	0.138	
E1	2.90	3.10	0.114	0.122	
E2	1.64	1.98	0.065	0.078	
е	0.65 BSC		0.026 BSC		
Н	0.32	0.52	0.013	0.020	
K	0.59	0.79	0.023	0.031	
L	0.25	0.55	0.010	0.022	

# **RECOMMENDED LAND PATTERN**



UNIT: mm



# XPX7528RX

#### 30V N-Channel Enhancement Mode Power MOSFET

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	<b>245</b> ℃ <b>±5</b> ℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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